



MSA MegaBooth in the M&M 2010 Exhibit Hall

Open during all
exhibit hall hours

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Registration, hotel and all program and meeting
details at www.microscopy.org/MandM/2010.

The **MSA MegaBooth** showcases all that MSA membership has to offer. If you are currently a member, stop by to catch up on all the new society developments. If you're not a member, now is the time to join! Member information available at Regular, Sustaining (corporate) and Student levels.

Sign up for **EXHIBITOR TUTORIALS** here! These popular sessions are presented on Monday, Tuesday and Wednesday evenings after the exhibit hall has closed for the day. Don't miss out – advance registration is required!

The **INTERNET CAFÉ** is open to all meeting attendees and provides FREE wireless internet during all exhibit hall hours. Lots of places to sit and rest your feet for a few moments while you check your email or put the finishing touches on your talk.

The **TECHNOLOGISTS' FORUM (TF)**: Attention Technologists! Stop by to find out how you can grow and develop your skills, your professional career and your network by joining the Forum!

The **PLACEMENT OFFICE** is MSA's job-listing service. Post a job, peruse job listings, post a resume, and/or find that perfect candidate for your job opening. All for FREE during the meeting!

Check out the **BOOK DISPLAY** – publisher-donated books, divided into biological/physical topics. Several new titles added every year!

MSA's **DVD LIBRARY** contains hundreds of titles on all aspects of microscopy. Browse the collection at your leisure and view samples to see content. DVDs can be purchased online via the MSA website.

CERTIFICATION BOARD – Find out about MSA's certification program for Electron Microscopy Technologists and how being certified can help you in your next job search!

MICROSCOPY TODAY and **MICROSCOPY and MICROANALYSIS** are the society's two publications – one a magazine format, the other a peer-reviewed scientific journal. Information for authors and advertisers is available here.

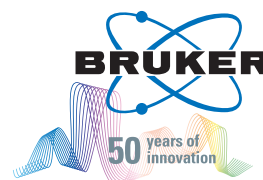
Project MICRO (Microscopy In Curriculum – Research Outreach) – MSA's middle-school educational outreach program. Browse the materials and find out how to start an outreach in your local area. Get details on the special programming at the M&M meeting for educators and kids of all ages.



Microscopy Society of America

For more information,
visit www.microscopy.org!

Bruker Nano

The image shows two 3D topography maps of a sample surface, rendered in a color gradient from blue (low) to red and yellow (high). The maps are set against a background of a blue, wavy, textured surface. The topography maps show a complex, irregular surface with various peaks and valleys.

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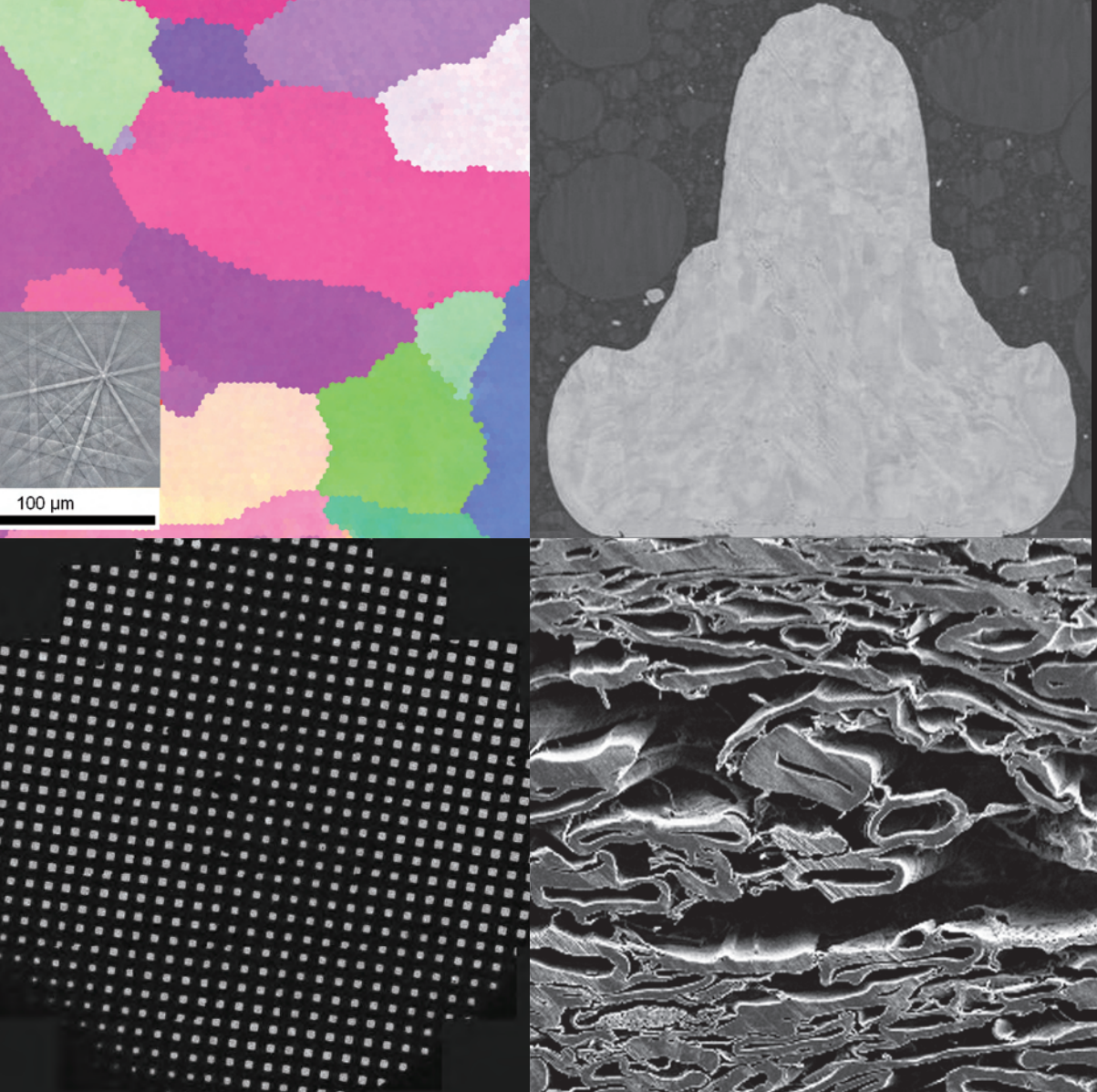
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Top images (left to right): Al-alloy; Gold wire bonding. Bottom images (left to right): Montage overview of plunge frozen grid; Paper.



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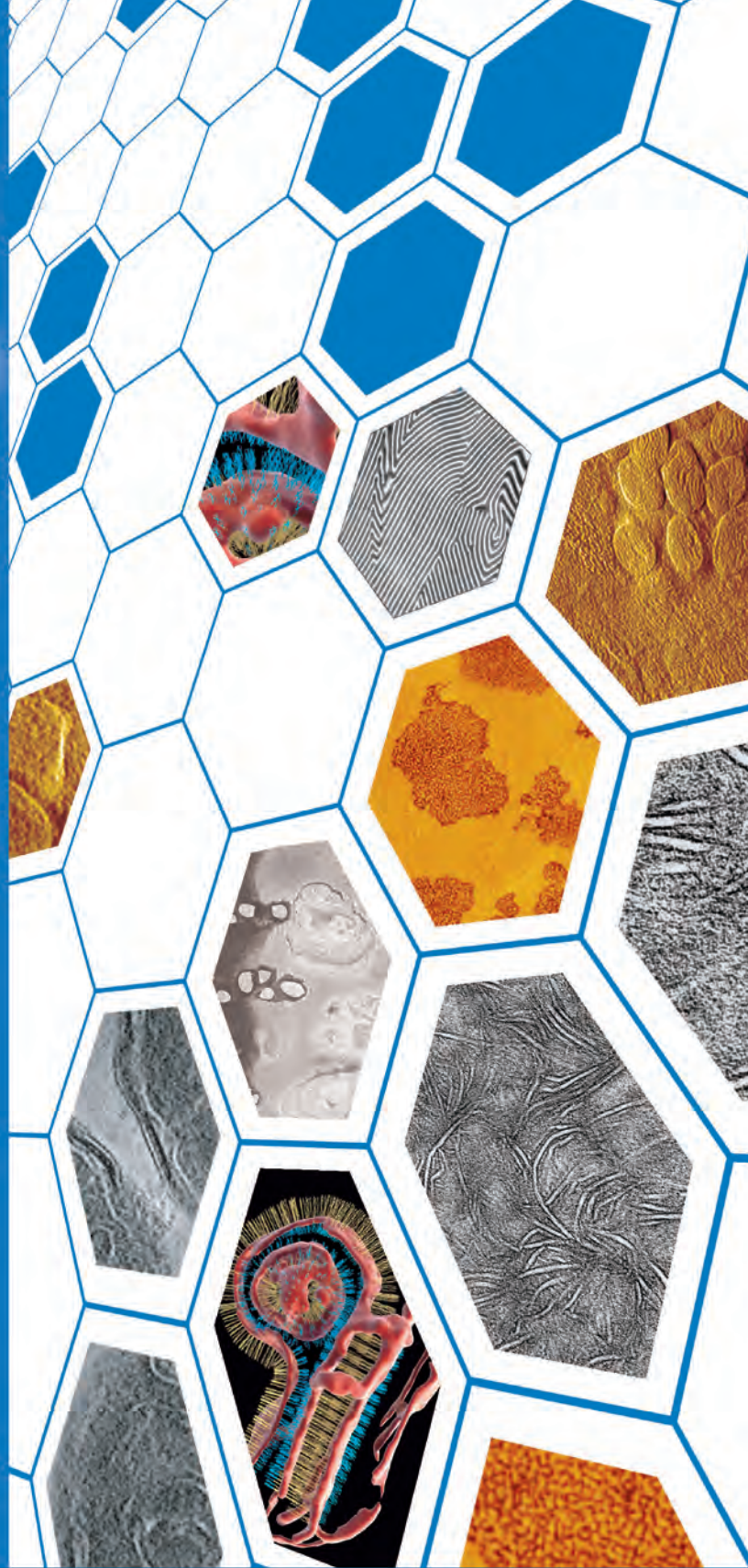
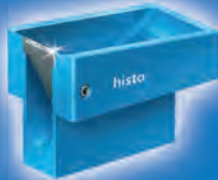
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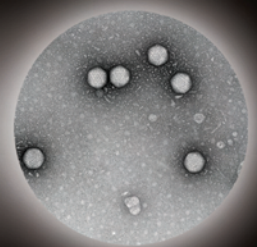
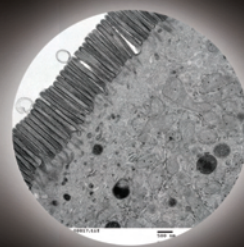
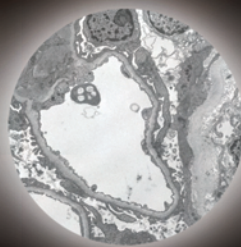
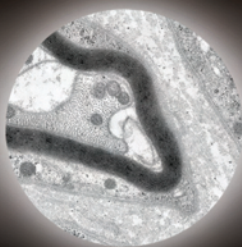
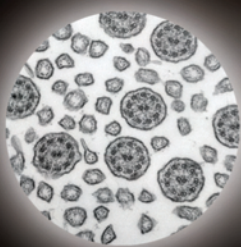
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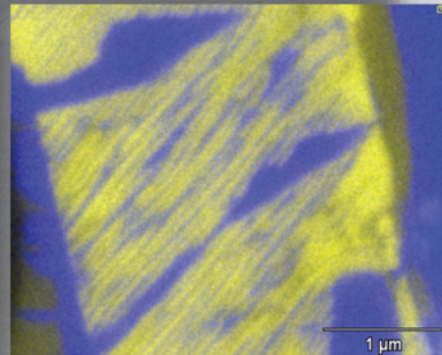
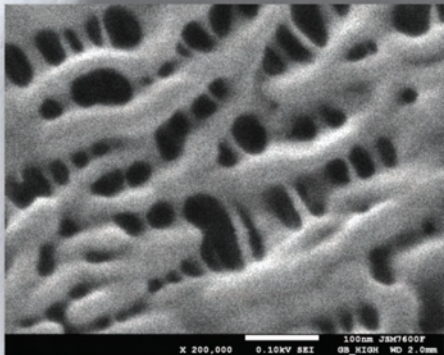
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EDS map of TiO_2 in FeO_x with $<100nm$ spatial resolution $30,000x$

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1-3 nm twinning in mineral BSE image

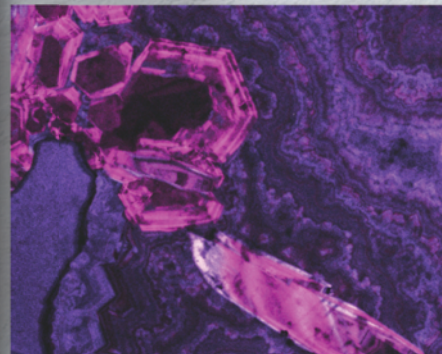
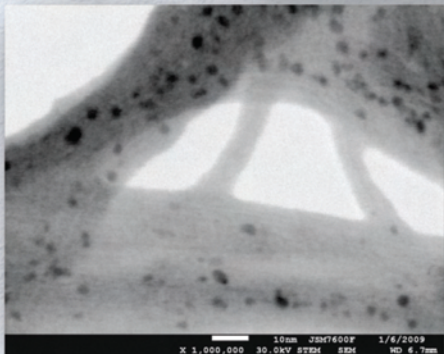


EBSD

Orientation map of Ni alloy

STEM

CNT with 1-3 nm Pt nanoparticles



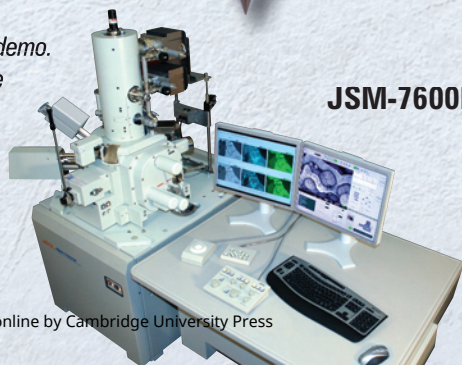
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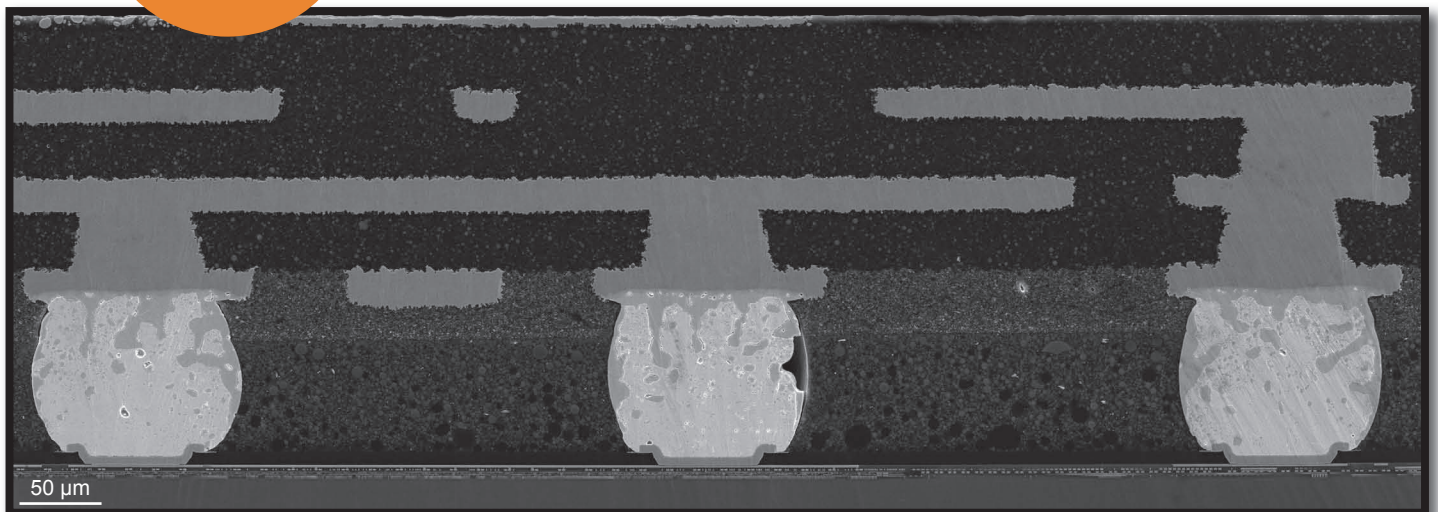
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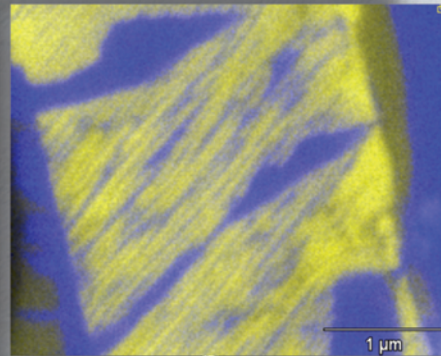
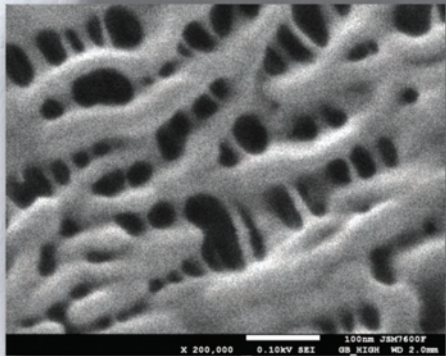
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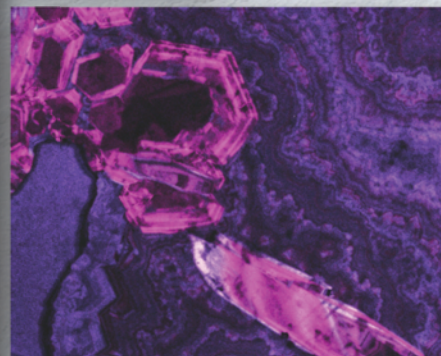
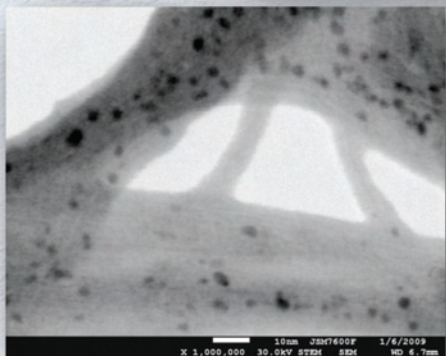


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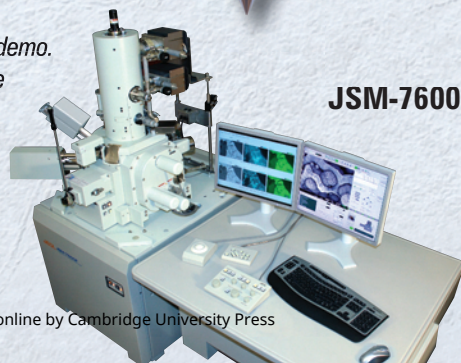
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